## Search Notes Application/Control No. Applicant(s)/Patent Under Reexamination CHOWN, DAVID Examiner Liu, Li 2613

SEARCHED					
Class	Subclass	Date	Examiner		
372	102	08/03/2006	LL		
398	41-43, 152, 129, 58, 122, 125	08/03/2006,	LL		
		02/08/2007			
385	12, 24, 93, 49	08/03/2006,	LL		
		02/08/2007			
250	25	08/03/2006	LL		

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST				
USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	08/03/2006, 02/08/2007, 11/27/2007, 5/31-6/13, 2008	LL		
Google	08/03/2006	LL		
IEEE	08/03/2006	LL		

	INTERFERENCE SEAF	RCH	
Class	Subclass	Date	Examiner

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